



IMPORTANT NOTICE

10 December 2015

1. Global joint venture starts operations as WeEn Semiconductors

Dear customer,

As from November 9th, 2015 NXP Semiconductors N.V. and Beijing JianGuang Asset Management Co. Ltd established Bipolar Power joint venture (JV), **WeEn Semiconductors**, which will be used in future Bipolar Power documents together with new contact details.

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Thank you for your cooperation and understanding,

WeEn Semiconductors



BYV32E-200

Dual rugged ultrafast rectifier diode, 20 A, 200 V

Rev. 04 — 27 February 2009

Product data sheet

1. Product profile

1.1 General description

Ultrafast dual epitaxial rectifier diode in a SOT78 (TO-220AB) plastic package.

1.2 Features and benefits

- High reverse voltage surge capability
- High thermal cycling performance
- Low thermal resistance
- Soft recovery characteristic minimizes power consuming oscillations
- Very low on-state loss

1.3 Applications

- Output rectifiers in high-frequency switched-mode power supplies

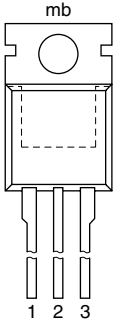
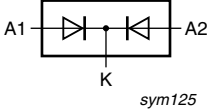
1.4 Quick reference data

Table 1. Quick reference

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|--------------------------------|---------------------------------|---|-----|------|------|------|
| V_{RRM} | repetitive peak reverse voltage | | - | - | 200 | V |
| $I_{O(AV)}$ | average output current | square-wave pulse; $\delta = 0.5$; $T_{mb} \leq 115\text{ °C}$; both diodes conducting; see Figure 1 ; see Figure 2 | - | - | 20 | A |
| I_{RRM} | repetitive peak reverse current | $t_p = 2\ \mu\text{s}$; $\delta = 0.001$ | - | - | 0.2 | A |
| V_{ESD} | electrostatic discharge voltage | HBM; C = 250 pF; R = 1.5 k Ω ; all pins | - | - | 8 | kV |
| Dynamic characteristics | | | | | | |
| t_{rr} | reverse recovery time | $I_F = 1\text{ A}$; $V_R = 30\text{ V}$; $dI_F/dt = 100\text{ A}/\mu\text{s}$; $T_j = 25\text{ °C}$; ramp recovery; see Figure 5 | - | 20 | 25 | ns |
| | | $I_R = 1\text{ A}$; $I_F = 0.5\text{ A}$; $T_j = 25\text{ °C}$; step recovery; measured at reverse current = 0.25 A; see Figure 6 | - | 10 | 20 | ns |
| Static characteristics | | | | | | |
| V_F | forward voltage | $I_F = 8\text{ A}$; $T_j = 150\text{ °C}$; see Figure 4 | - | 0.72 | 0.85 | V |

2. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|------------------------|--|---|
| 1 | A1 | anode 1 |  |  |
| 2 | K | cathode | | |
| 3 | A2 | anode 2 | | |
| mb | K | mounting base; cathode | | |

SOT78
(TO-220AB; SC-46)

3. Ordering information

Table 3. Ordering information

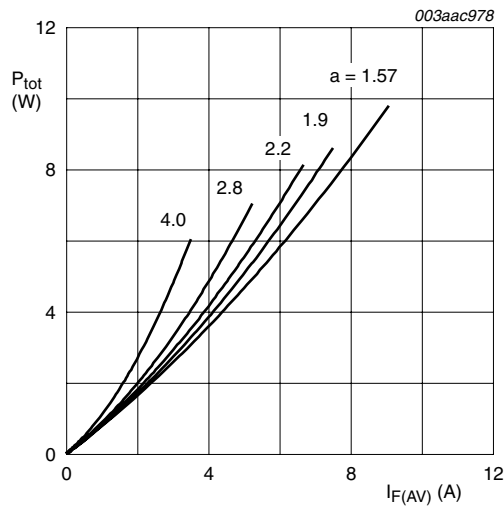
| Type number | Package | Description | Version |
|-------------|-----------|---|---------|
| | Name | | |
| BYV32E-200 | TO-220AB; | plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead | SOT78 |
| | SC-46 | | |

4. Limiting values

Table 4. Limiting values

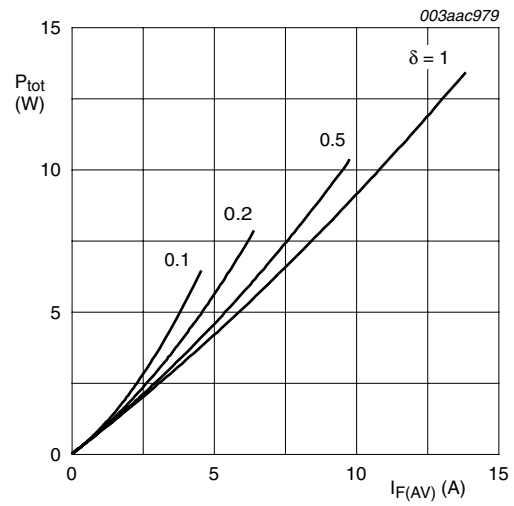
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-------------|-------------------------------------|---|-----|-----|------|
| V_{RRM} | repetitive peak reverse voltage | | - | 200 | V |
| V_{RWM} | crest working reverse voltage | | - | 200 | V |
| V_R | reverse voltage | DC | - | 200 | V |
| $I_{O(AV)}$ | average output current | square-wave pulse; $\delta = 0.5$; $T_{mb} \leq 115\text{ °C}$; both diodes conducting; see Figure 1 ; see Figure 2 | - | 20 | A |
| I_{FRM} | repetitive peak forward current | $\delta = 0.5$; $t_p = 25\ \mu\text{s}$; $T_{mb} \leq 115\text{ °C}$; per diode | - | 20 | A |
| I_{FSM} | non-repetitive peak forward current | $t_p = 8.3\text{ ms}$; sine-wave pulse; $T_{j(\text{init})} = 25\text{ °C}$; per diode | - | 137 | A |
| | | $t_p = 10\text{ ms}$; sine-wave pulse; $T_{j(\text{init})} = 25\text{ °C}$; per diode | - | 125 | A |
| I_{RRM} | repetitive peak reverse current | $\delta = 0.001$; $t_p = 2\ \mu\text{s}$ | - | 0.2 | A |
| I_{RSM} | non-repetitive peak reverse current | $t_p = 100\ \mu\text{s}$ | - | 0.2 | A |
| T_{stg} | storage temperature | | -40 | 150 | °C |
| T_j | junction temperature | | - | 150 | °C |
| V_{ESD} | electrostatic discharge voltage | HBM; C = 250 pF; R = 1.5 kΩ; all pins | - | 8 | kV |



$$a = \text{form factor} = I_{F(RMS)} / I_{F(AV)}$$

Fig 1. Forward power dissipation as a function of average forward current; sinusoidal waveform; maximum values



$$I_{F(AV)} = I_{F(RMS)} \times \sqrt{\delta}$$

Fig 2. Forward power dissipation as a function of average forward current; square waveform; maximum values

5. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|----------------|---|---|-----|-----|-----|------|
| $R_{th(j-mb)}$ | thermal resistance from junction to mounting base | with heatsink compound; both diodes conducting | - | - | 1.6 | K/W |
| | | with heatsink compound; per diode; see Figure 3 | - | - | 2.4 | K/W |
| $R_{th(j-a)}$ | thermal resistance from junction to ambient | | - | 60 | - | K/W |

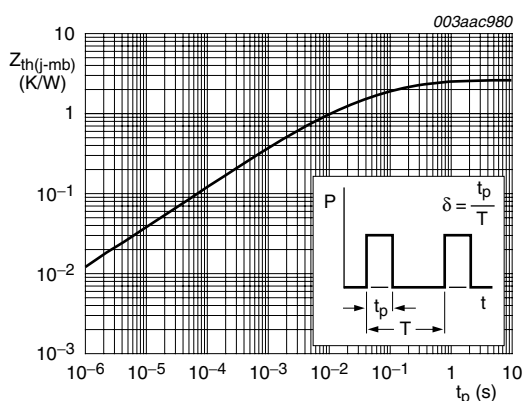
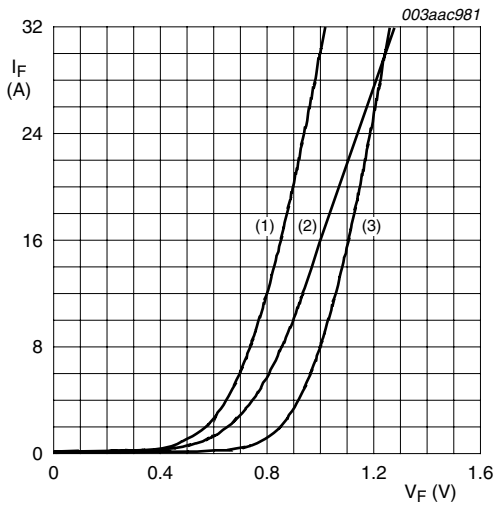


Fig 3. Transient thermal impedance from junction to mounting base as a function of pulse width

6. Characteristics

Table 6. Characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|--------------------------------|--------------------------|--|-----|------|------|---------------|
| Static characteristics | | | | | | |
| V_F | forward voltage | $I_F = 20\text{ A}; T_j = 25\text{ °C}$ | - | 1 | 1.15 | V |
| | | $I_F = 8\text{ A}; T_j = 150\text{ °C}$; see Figure 4 | - | 0.72 | 0.85 | V |
| I_R | reverse current | $V_R = 200\text{ V}; T_j = 100\text{ °C}$ | - | 0.2 | 0.6 | mA |
| | | $V_R = 200\text{ V}; T_j = 25\text{ °C}$ | - | 6 | 30 | μA |
| Dynamic characteristics | | | | | | |
| Q_r | recovered charge | $I_F = 2\text{ A}; V_R = 30\text{ V}; di_F/dt = 20\text{ A}/\mu\text{s}; T_j = 25\text{ °C}$ | - | 8 | 12.5 | nC |
| t_{rr} | reverse recovery time | $I_F = 1\text{ A}; V_R = 30\text{ V}; di_F/dt = 100\text{ A}/\mu\text{s};$ ramp recovery; $T_j = 25\text{ °C}$; see Figure 5 | - | 20 | 25 | ns |
| | | $I_F = 0.5\text{ A}; I_R = 1\text{ A};$ step recovery; measured at reverse current = 0.25 A; $T_j = 25\text{ °C}$; see Figure 6 | - | 10 | 20 | ns |
| V_{FR} | forward recovery voltage | $I_F = 1\text{ A}; di_F/dt = 10\text{ A}/\mu\text{s}; T_j = 25\text{ °C}$; see Figure 7 | - | - | 1 | V |



- (1) $T_j = 150\text{ }^\circ\text{C}$; typical values
- (2) $T_j = 150\text{ }^\circ\text{C}$; maximum values
- (3) $T_j = 25\text{ }^\circ\text{C}$; maximum values

Fig 4. Forward current as a function of forward voltage

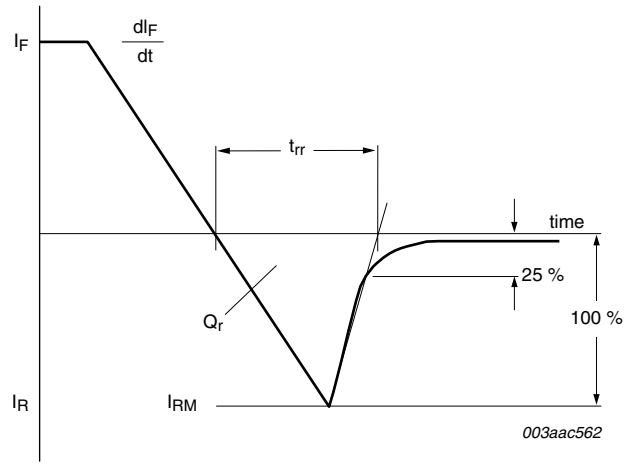


Fig 5. Reverse recovery definitions; ramp recovery

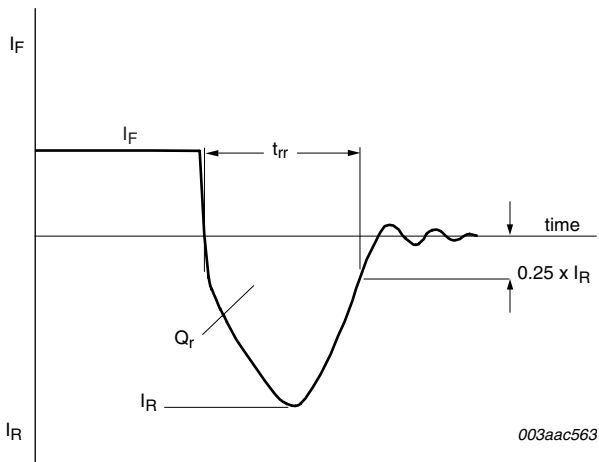


Fig 6. Reverse recovery definitions; step recovery

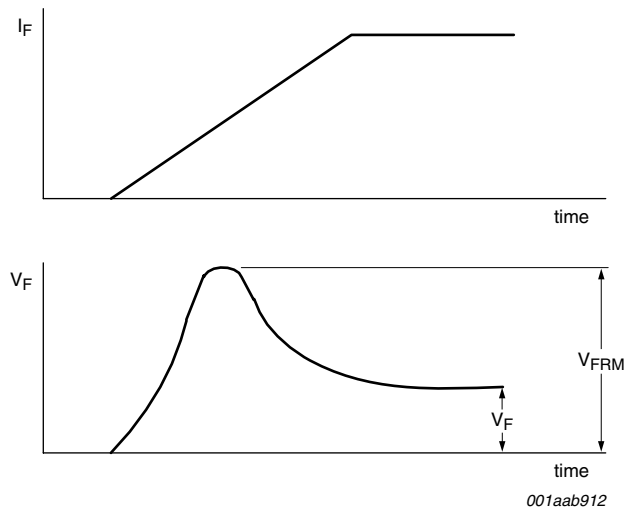


Fig 7. Forward recovery definitions

7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB

SOT78

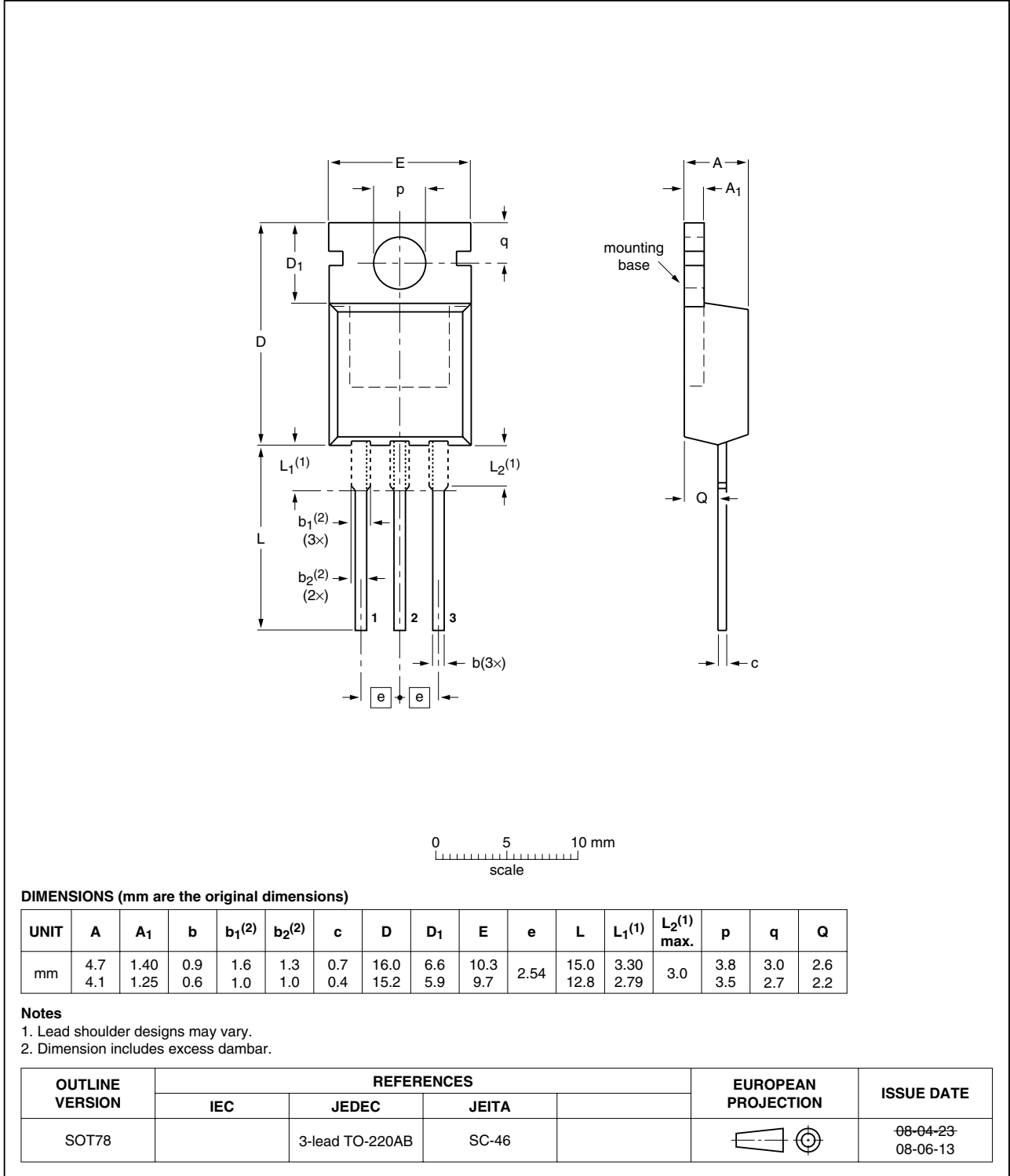


Fig 8. Package outline SOT78 (TO-220AB)

8. Revision history

Table 7. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|------------------|--------------|---|---------------|------------------|
| BYV32E-200_4 | 20090227 | Product data sheet | - | BYV32E_SERIES_3 |
| Modifications: | | <ul style="list-style-type: none"> • The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Legal texts have been adapted to the new company name where appropriate. • Package outline updated. • Type number BYV32E-200 separated from data sheet BYV32E_SERIES_3 | | |
| BYV32E_SERIES_3 | 20010301 | Product specification | - | BYV32E_SERIES_2 |
| BYV32E_SERIES_2 | 19980701 | Product specification | - | BYV32EB_SERIES_1 |
| BYV32EB_SERIES_1 | 19960801 | Product specification | - | - |

9. Legal information

9.1 Data sheet status

| Document status ^{[1][2]} | Product status ^[3] | Definition |
|-----------------------------------|-------------------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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